

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/697,534	SHATTIL, STEVE J.	
Examiner		Art Unit		Page 1 of 1
Kevin Y. Kim		2611		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wiegandt et al, "Overcoming peak-to-peak average power ratio issues in OFDM via carrier-interferometry codes," 2001, IEEE, vol.2, pp. 660-663.
	V	
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.